

## IRF2903ZPbF

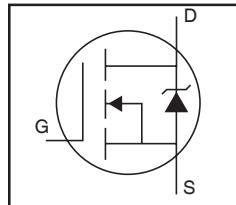
### Features

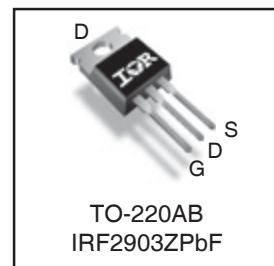
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free

### Description

This HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

### HEXFET® Power MOSFET

	$V_{DSS} = 30V$
	$R_{DS(on)} = 2.4m\Omega$
	$I_D = 75A$



G	D	S
Gate	Drain	Source

### Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	260	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	180	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	75	
$I_{DM}$	Pulsed Drain Current ①	1020	
$P_D @ T_C = 25^\circ C$	Power Dissipation	290	W
	Linear Derating Factor	2.0	W/ $^\circ C$
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$ (Thermally limited)	Single Pulse Avalanche Energy ②	290	mJ
$E_{AS}$ (Tested )	Single Pulse Avalanche Energy Tested Value ③	820	
$I_{AR}$	Avalanche Current ④	See Fig.12a, 12b, 15, 16	A
$E_{AR}$	Repetitive Avalanche Energy ⑤		mJ
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 175	$^\circ C$
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting Torque, 6-32 or M3 screw ⑦	10 lbf•in (1.1N•m)	

### Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ⑧	—	0.51	$^\circ C/W$
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface ⑨	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient ⑩	—	62	

# IRF2903ZPbF

International  
Rectifier

## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

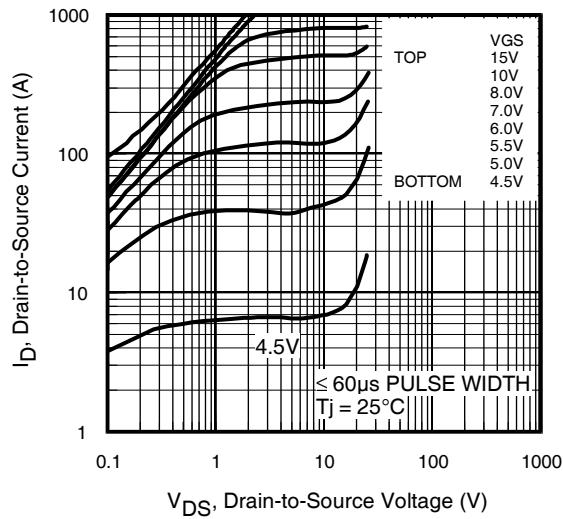
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	30	—	—	V	$V_{\text{GS}} = 0\text{V}$ , $I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.021	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1\text{mA}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	1.9	2.4	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}$ , $I_D = 75\text{A}$ ③
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{\text{DS}} = V_{\text{GS}}$ , $I_D = 150\mu\text{A}$
$g_{\text{fs}}$	Forward Transconductance	120	—	—	S	$V_{\text{DS}} = 10\text{V}$ , $I_D = 75\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	20	$\mu\text{A}$	$V_{\text{DS}} = 30\text{V}$ , $V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 30\text{V}$ , $V_{\text{GS}} = 0\text{V}$ , $T_J = 125^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{\text{GS}} = -20\text{V}$
$Q_g$	Total Gate Charge	—	160	240	nC	$I_D = 75\text{A}$
$Q_{\text{gs}}$	Gate-to-Source Charge	—	51	—		$V_{\text{DS}} = 24\text{V}$
$Q_{\text{gd}}$	Gate-to-Drain ("Miller") Charge	—	58	—		$V_{\text{GS}} = 10\text{V}$ ③
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	24	—	ns	$V_{\text{DD}} = 15\text{V}$
$t_r$	Rise Time	—	100	—		$I_D = 75\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	48	—		$R_G = 3.2 \Omega$
$t_f$	Fall Time	—	37	—		$V_{\text{GS}} = 10\text{V}$ ③
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{\text{iss}}$	Input Capacitance	—	6320	—	pF	$V_{\text{GS}} = 0\text{V}$
$C_{\text{oss}}$	Output Capacitance	—	1980	—		$V_{\text{DS}} = 25\text{V}$
$C_{\text{rss}}$	Reverse Transfer Capacitance	—	1100	—		$f = 1.0\text{MHz}$
$C_{\text{oss}}$	Output Capacitance	—	5930	—		$V_{\text{GS}} = 0\text{V}$ , $V_{\text{DS}} = 1.0\text{V}$ , $f = 1.0\text{MHz}$
$C_{\text{oss}}$ eff.	Effective Output Capacitance	—	2010	—		$V_{\text{GS}} = 0\text{V}$ , $V_{\text{DS}} = 24\text{V}$ , $f = 1.0\text{MHz}$
$C_{\text{oss}}$ eff.	Effective Output Capacitance	—	3050	—		$V_{\text{GS}} = 0\text{V}$ , $V_{\text{DS}} = 0\text{V}$ to $24\text{V}$ ④

## Source-Drain Ratings and Characteristics

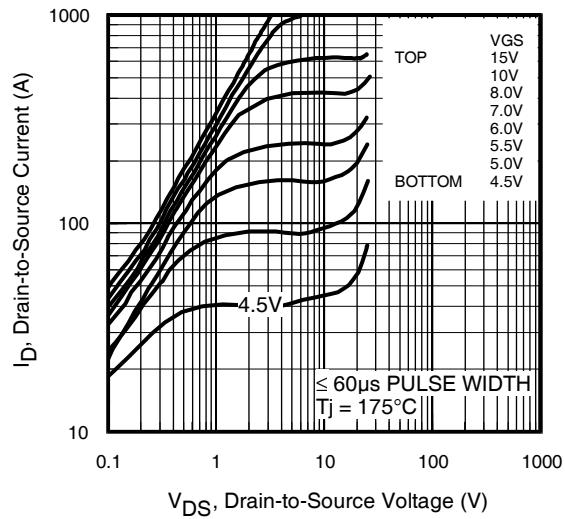
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	75	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{\text{SM}}$	Pulsed Source Current (Body Diode) ①	—	—	1020		
$V_{\text{SD}}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}$ , $I_S = 75\text{A}$ , $V_{\text{GS}} = 0\text{V}$ ③
$t_{\text{rr}}$	Reverse Recovery Time	—	34	51	ns	$T_J = 25^\circ\text{C}$ , $I_F = 75\text{A}$ , $V_{\text{DD}} = 15\text{V}$
$Q_{\text{rr}}$	Reverse Recovery Charge	—	29	44	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③
$t_{\text{on}}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

### Notes:

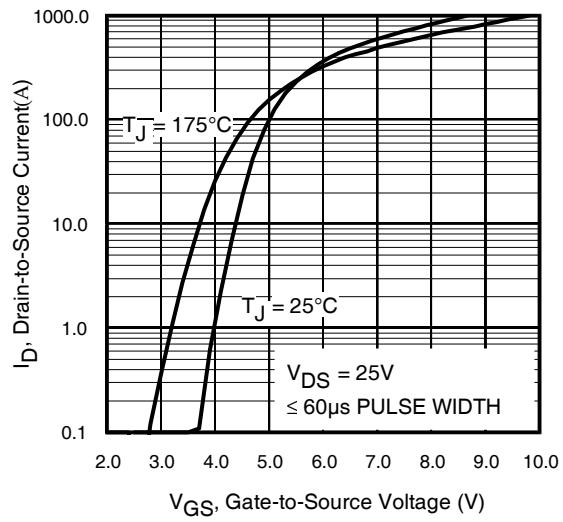
- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by  $T_{J\text{max}}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.10\text{mH}$   $R_G = 25\Omega$ ,  $I_{AS} = 75\text{A}$ ,  $V_{\text{GS}} = 10\text{V}$ . Part not recommended for use above this value.
- ③ Pulse width  $\leq 1.0\text{ms}$ ; duty cycle  $\leq 2\%$ .
- ④  $C_{\text{oss}}$  eff. is a fixed capacitance that gives the same charging time as  $C_{\text{oss}}$  while  $V_{\text{DS}}$  is rising from 0 to 80%  $V_{\text{DSS}}$ .
- ⑤ Limited by  $T_{J\text{max}}$ , see Fig. 12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑥ This value determined from sample failure population. 100% tested to this value in production.
- ⑦ This is only applied to TO-220AB package.
- ⑧  $R_\theta$  is measured at  $T_J$  approximately  $90^\circ\text{C}$



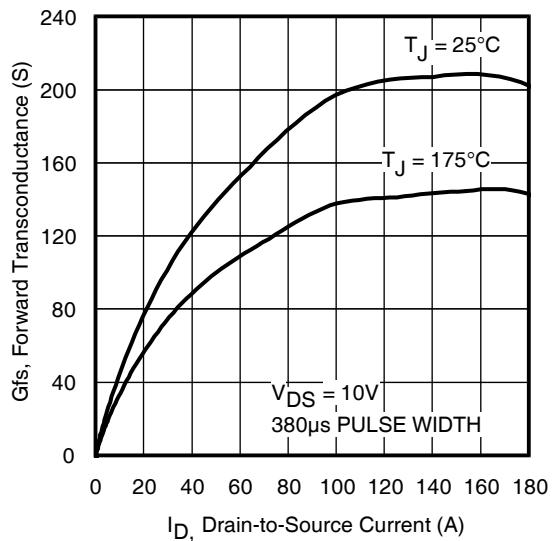
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



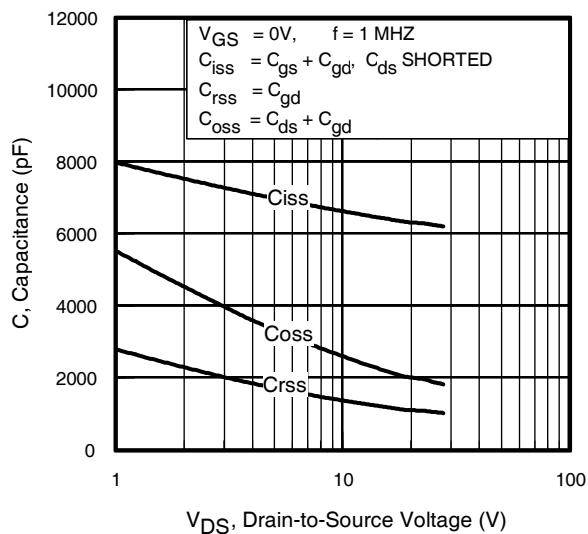
**Fig 3.** Typical Transfer Characteristics



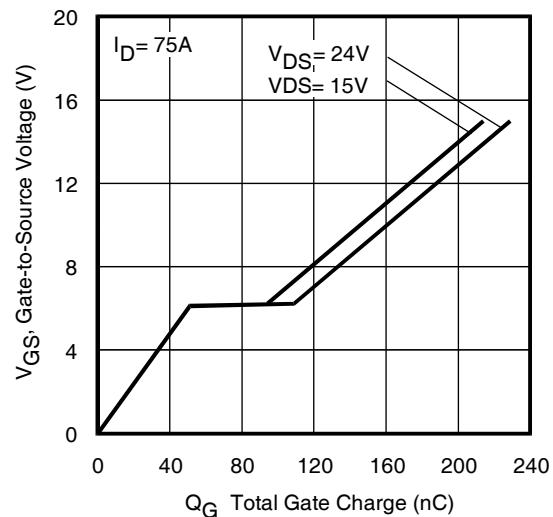
**Fig 4.** Typical Forward Transconductance Vs. Drain Current

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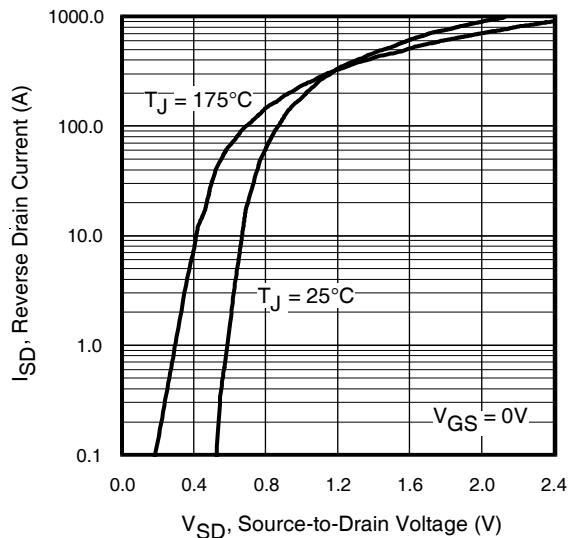
International  
**IR** Rectifier



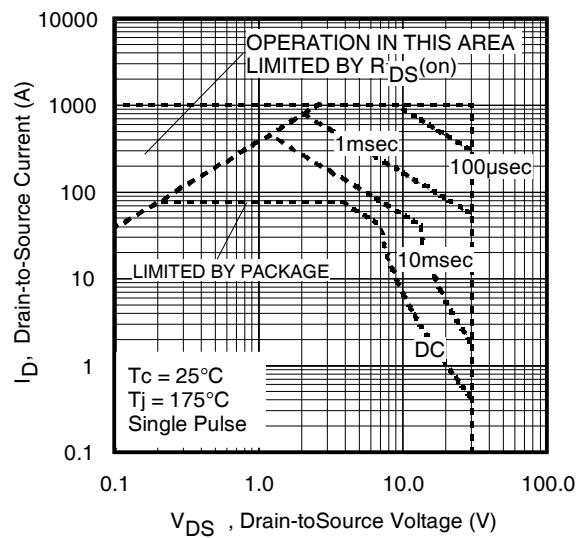
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



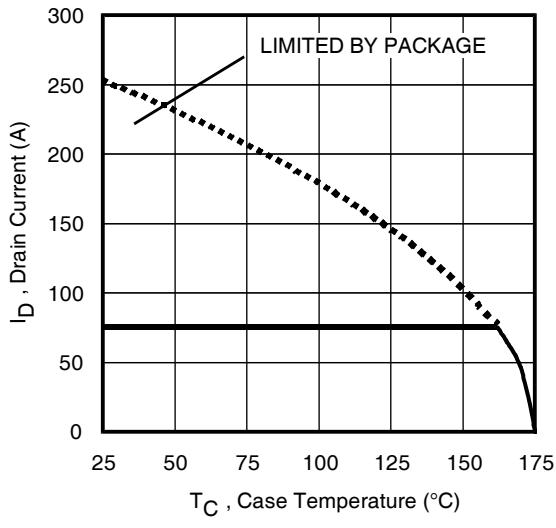
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



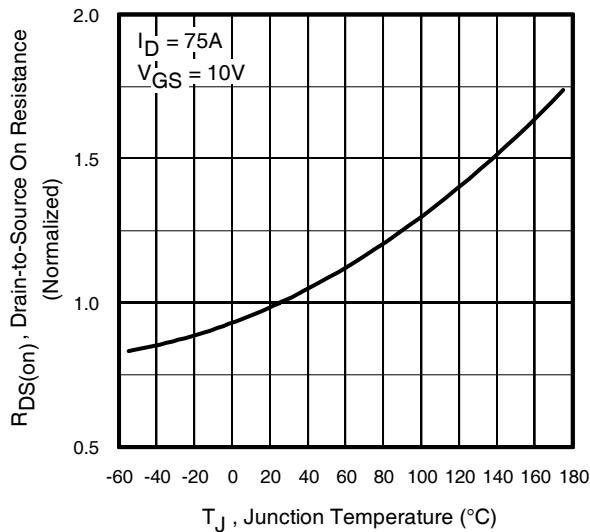
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



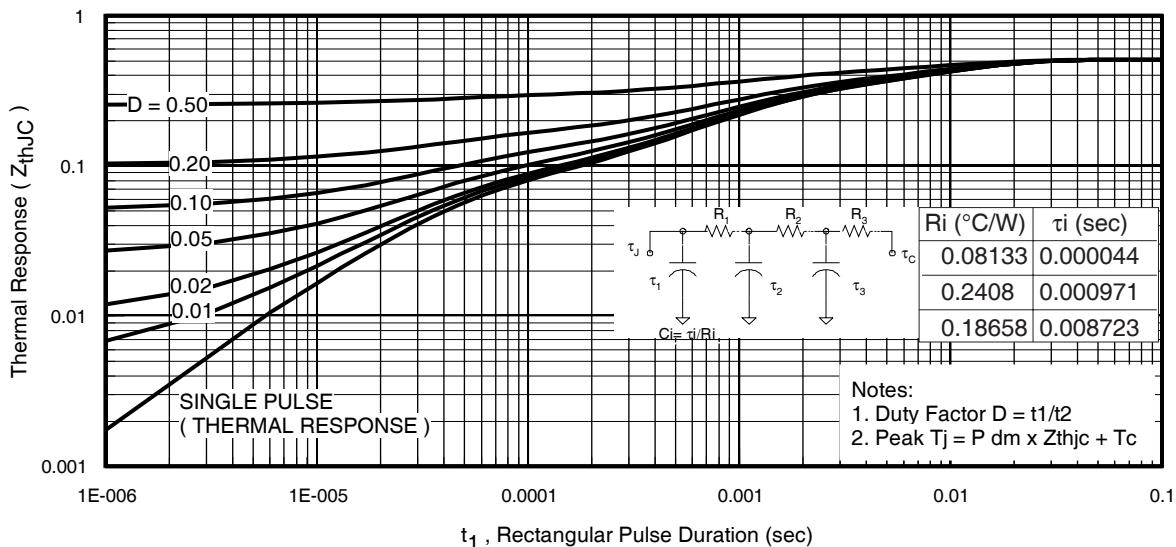
**Fig 8.** Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs.  
Case Temperature



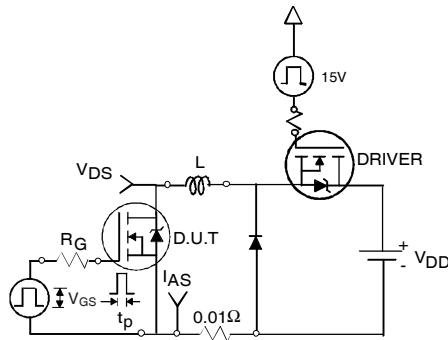
**Fig 10.** Normalized On-Resistance  
Vs. Temperature



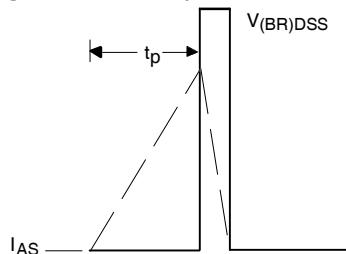
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

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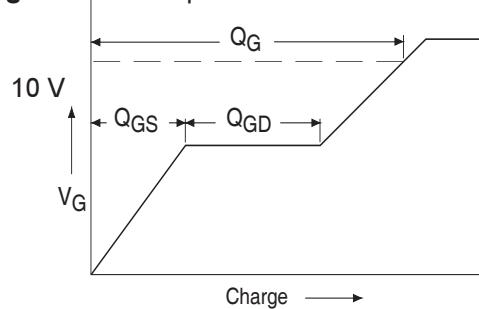
International  
Rectifier



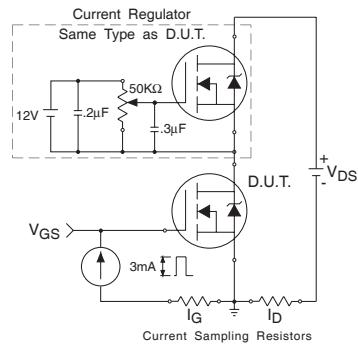
**Fig 12a.** Unclamped Inductive Test Circuit



**Fig 12b.** Unclamped Inductive Waveforms

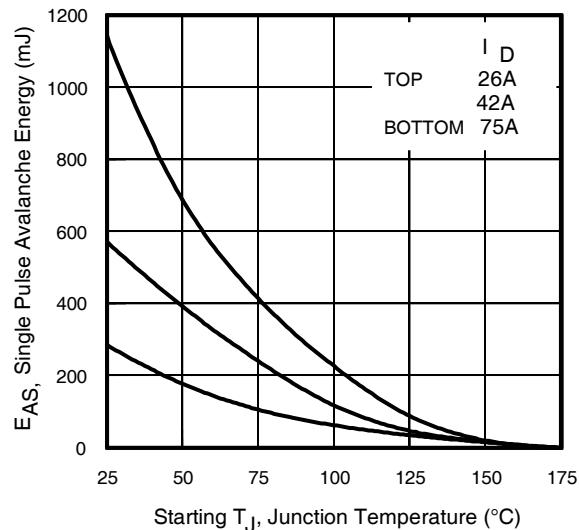


**Fig 13a.** Basic Gate Charge Waveform

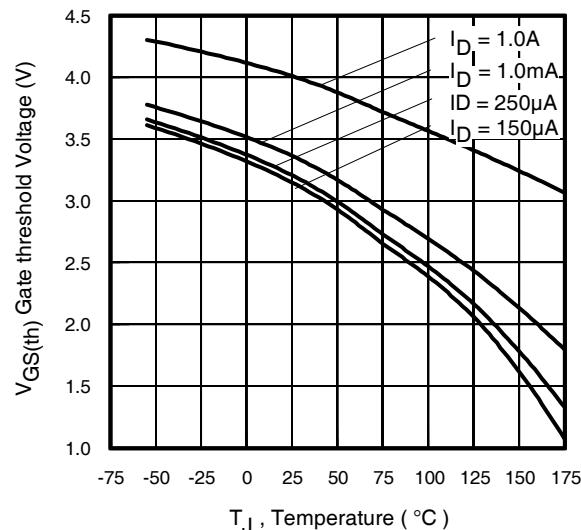


**Fig 13b.** Gate Charge Test Circuit

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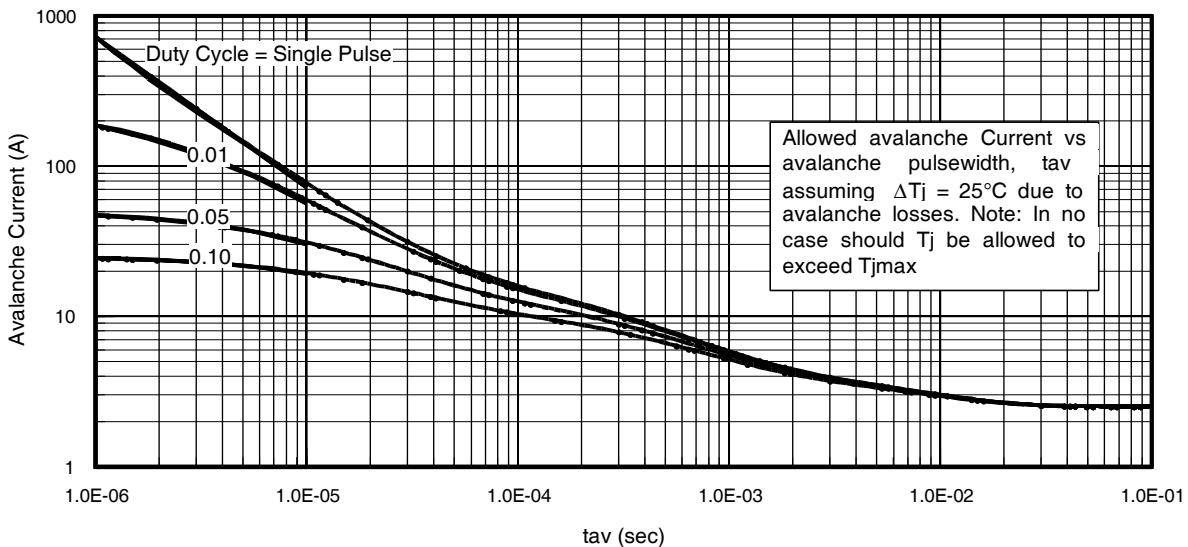


**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

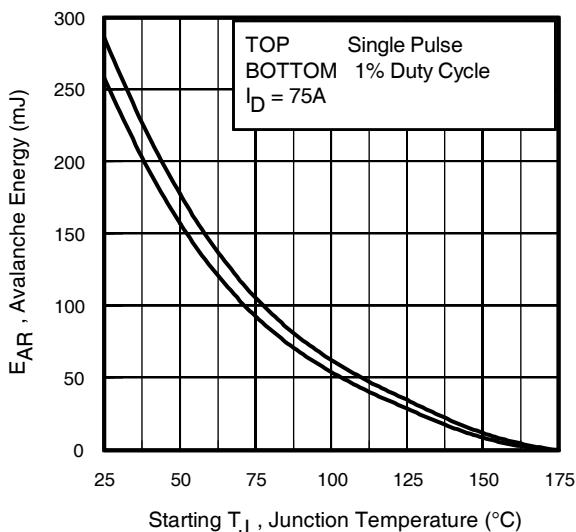


**Fig 14.** Threshold Voltage Vs. Temperature

[www.irf.com](http://www.irf.com)



**Fig 15.** Typical Avalanche Current Vs.Pulsewidth



**Fig 16.** Maximum Avalanche Energy Vs. Temperature

**Notes on Repetitive Avalanche Curves , Figures 15, 16:  
 (For further info, see AN-1005 at [www.irf.com](http://www.irf.com))**

1. Avalanche failures assumption:  
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4.  $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
5.  $BV$  = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as  $25^\circ\text{C}$  in Figure 15, 16).
- $t_{av}$  = Average time in avalanche.
- $D$  = Duty cycle in avalanche =  $t_{av} \cdot f$
- $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see figure 11)

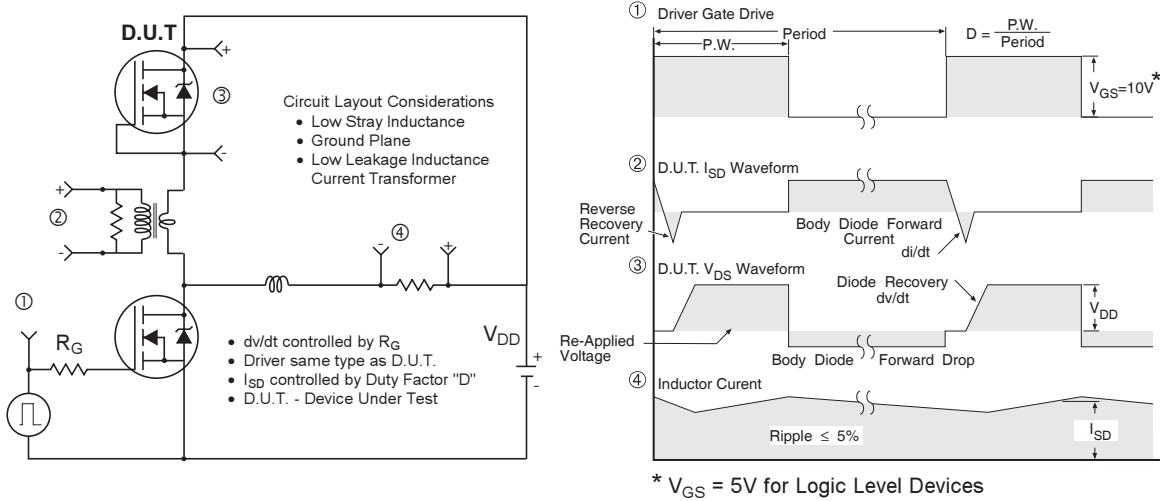
$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

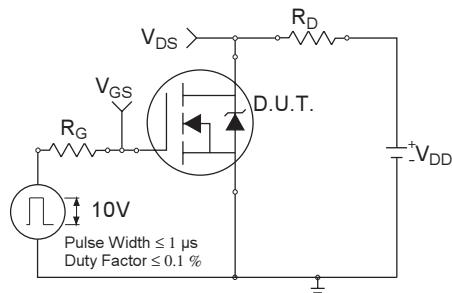
$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

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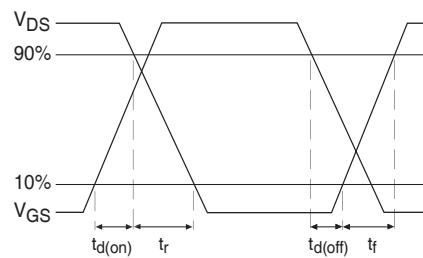
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**Fig 17.** Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs



**Fig 18a.** Switching Time Test Circuit

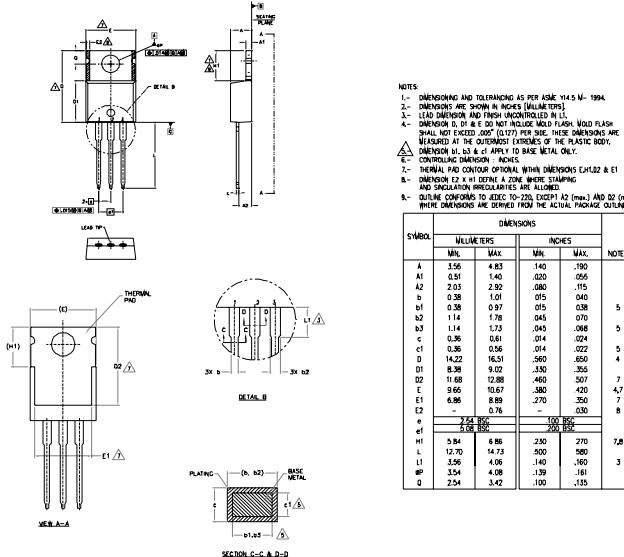


**Fig 18b.** Switching Time Waveforms

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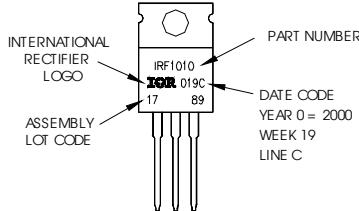
TO-220AB Package Outline(Dimensions are shown in millimeters (inches))



## TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010  
 LOT CODE 1789  
 ASSEMBLED ON WW19, 2000  
 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position  
 indicates "Lead-Free"



TO-220AB package is not recommended for Surface Mount Application.

### Notes:

1. For an Automotive Qualified version of this part please see <http://www.irf.com/product-info/auto/>
2. For the most current drawing please refer to IR website at <http://www.irf.com/package/>

Data and specifications subject to change without notice.  
 This product has been designed and qualified for the Industrial market.  
 Qualification Standards can be found on IR's Web site.

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